

AMENDED

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Form PTO-1449 (modified)

List of Patents and Publications for Applicant's

Atty. Docket No.
METR:003

Serial No.
10/668,642

Applicant
Dale A. Harrison

Filing Date:
September 23, 2003

Group:
Unknown

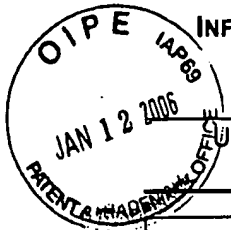
INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

U.S. Patent Documents
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Foreign Patent Documents
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Other Art
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U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
	AI						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	BI						

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	McPherson Product Brochure "Reflectometer for Sample Analysis," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
CH	C1A	McPherson Product Brochure "Spectral Reflectometer," McPherson, Inc., Massachusetts, November 12, 2001, 1 pg.
	C2	McPherson Product Brochure "VUVaS Spectrophotometers for 115 nm to >380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-4 pps.
	C3	McPherson Product Brochure "VUVaS Spectrophotometers, Made to Measure 115-380 nm," McPherson, Inc., Massachusetts, Published Prior to September 23, 2003, 1-8 pps.
	C4	Acton Research Product Brochure "Acton Research Purged DAMS Optical Measurement System," Acton Research Corporation, Massachusetts, Published Prior to September 23, 2003, 1-2 pps.
CH	C5	"The Thin Film tool for next generation lithography at 157nm," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet On February 19, 2002, 1pg.
CH	C6	"SE and GXR combined on the same instrument," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet on February 19, 2002, 1pg.
CH	C7	"The ideal Thin Film characterization unit for Development and Pilot Line environment," Web page from http://www.sopra-sa.com , Sopra, Printed From Internet on February 19, 2002, 1 pg.

Examiner: **CONSTANTINE HANNAHER**

Date Considered: **FEB 14 2006**

EXAMINER: initial if reference considered, whether or not citation is in conformance with MPEP609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. Patent Documents See Page	Foreign Patent Documents See Page	Other Art See Pages 1-2	

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
Exam. Init.	Ref. Des.	Citation
CH	C8	"VUV-VASE™, The Award Winning VUV-VASE™ is the latest addition to our line of Spectroscopic Ellipsometers," Web pages from http://www.jawoolam.com , J.A. Woollam Company, Nebraska, Printed From Internet on November 5, 2002, 1-2 pps.
CH	C9	"Vacuum UV Spectroscopic Ellipsometers," Web pages from http://www.sentech.de , Sentech Instruments, Printed From Internet on February 20, 2002, 1-3 pps.

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2877**INFORMATION DISCLOSURE STATEMENT**

(Use several sheets if necessary)

U.S. Patent Documents
See Page 1Foreign Patent Documents
N/AOther Art
See Page 1**U.S. Patent Documents**

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date if App.
CH	A31	6,710,865 B2	3/23/04	Forouhi et al.			9/14/01
CH	A32	6,313,466 B1	11/6/01	Olsen et al.			5/12/99
CH	A33	5,607,800 A	3/4/97	Ziger			2/15/95
CH	A34	4,984,894 A	1/15/91	Kondo			8/16/89
CH	A35	4,368,983 A	1/18/83	Bennett			11/13/80

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No

Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
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